

**ATTORNEY DOCKET NO.
1105-CA (formerly 50246-076)**

PATENT

EXPEDITED PROCEDURE

IN THE CLAIMS

This listing of claims will replace all prior versions, and listings, of claims in the Application and reflects amendments to claims 11 and 12:

Claim 1 (previously presented): An apparatus for testing an integrated circuit to determine if 1/f noise of a circuit to be tested on said integrated circuit is within specifications, comprising:

- a. a mechanism for applying a preselected offset inside a chopper stabilized circuit forming part of said circuit to be tested; and
- b. a circuit for checking whether the output of said chopper stabilized circuit is within a predetermined offset specification for the chopper stabilized circuit.

Claim 2 (previously presented) Apparatus of claim 1 in which said preselected offset has a value greater than expected in normal use with the chopper stabilized circuit.

Claim 3 (previously presented) Apparatus of claim 1 in which the circuit to be tested passes a 1/f noise test if the output of the chopper circuit is within the predetermined offset specification.

Claim 4 (original) Apparatus of claim 1 in which said chopper stabilized circuit is a chopper stabilized amplifier.

Claim 5 (previously presented) A method for testing an integrated circuit to determine if 1/f noise of a circuit to be tested on said integrated circuit is within specifications comprising:

- a. applying a preselected offset inside a chopper stabilized circuit forming part of said circuit to be tested; and
- b. checking whether the out put of said chopper stabilized circuit is within a predetermined offset specification for the chopper stabilized circuit.

Claim 6 (previously presented) Method of claim 5 in which said preselected offset has a value greater than expected in normal use with the chopper stabilized circuit.

ATTORNEY DOCKET NO.
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Claim 7 (previously presented) Method of claim 5 in which the circuit to be tested passes a 1/f noise test if the output of the chopper stabilized circuit is within the predetermined offset specification.

Claim 8 (original) The method of claim 5 in which said chopper stabilized circuit is a chopper stabilized amplifier.

Claim 9 (original) A method of testing for 1/f noise performance in less than 1/f time comprising the step of using proper offset removal of a chopper stabilized circuit as a surrogate for measuring for 1/f noise.

Claim 10 (canceled)

Claim 11 (canceled)

Claim 12 (currently amended) ~~The method of claim 11 comprising~~ A method of testing an integrated circuit comprising:

(a) external to the circuit, observing an output of a chopper stabilized circuit;

(b) external to the circuit, controlling the offset of the chopper stabilized circuit; and

(c) using offset removal as a surrogate for 1/f noise performance of the chopper stabilized circuit.

Claim 13 (previously presented) The method of claim 12 wherein the circuit under test passes a 1/f noise test if the output of the chopper stabilized circuit is within a predetermined offset specification.

Claim 14 (previously presented) An apparatus for testing an integrated circuit to determine if said integrated circuit is within specifications comprising:

ATTORNEY DOCKET NO.
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a. a mechanism for selectively adding additional offset, while the test is conducted, inside a chopper stabilized circuit forming part of said circuit to be tested; and

b. a circuit for checking whether the output of said chopper stabilized circuit is within a predetermined limit.

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Claim ¹²~~15~~ (previously presented) Apparatus of claim ¹¹~~14~~ in which the additional offset combined with any internal offset of the chopper stabilized circuit has a value greater than expected in normal use with a chopper stabilized circuit.

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Claim ~~16~~ (previously presented) A method for testing an integrated circuit to determine if said integrated circuit is within specifications, comprising:

a. selectively adding additional offset, while the test is conducted, inside a chopper stabilized circuit forming part of said circuit to be tested; and

b. checking whether the output level of said chopper stabilized circuit is within a predetermined limit.

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Claim ~~17~~ (previously presented) The method of claim ¹³~~16~~ in which the additional offset combined with any internal offset of the chopper stabilized circuit has a value greater than expected in normal use with a chopper stabilized circuit.
